

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. .... Filed Herewith  
Filing Date .... Filed Herewith  
Inventor .... Luan C. Tran  
Assignee .... Micron Technology, Inc.  
Group Art Unit .... Unknown  
Examiner .... Unknown  
Attorney's Docket No. .... MI22-2339  
Title: Methods of Forming Conductive Capacitor Plugs, Methods of Forming Capacitor  
Contact Openings, and Methods of Forming Memory Arrays

**INFORMATION DISCLOSURE STATEMENT**  
**PURSUANT TO 37 C.F.R. §§ 1.56, 1.97 AND 1.98**

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. No admission is made regarding whether all the submitted references are prior art.


The listed references were cited by, or submitted to, the Office in the parent, co-pending application of the above-identified application. The above-identified application is a continuation application of co-pending application Serial No. 09/359,956, filed July 22, 1999. Such prior disclosure is sufficient for the above-identified application as far as copies of the references are concerned.

37 C.F.R. § 1.98(d) and MPEP § 609(2). **EV317135518**

Citation of these references is respectfully requested.

Respectfully submitted,

Dated: 7/3/03

By:   
James D. Shaurette  
Reg. No. 39,833

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2339	SERIAL NO. Filed Herewith		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Luan C. Tran			
				FILING DATE Filed Herewith	GROUP Unknown		
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	5,780,338	07/14/98	Jeng et al.			
	AB	5,706,164	01/06/98	Jeng			
	AC	5,688,713	11/18/97	Linliu et al.			
	AD	5,627,095	05/06/97	Koh et al.			
	AE	5,488,011	01/30/96	Figura et al.			
	AF	5,383,088	01/17/95	Chapple-Sokol et al.			
	AG	5,874,756	02/23/99	Ema et al.			
	AH	5,837,577	11/17/98	Cherng			
	AI	5,688,713	11/18/97	Linliu et al.			
	AJ	5,663,092	09/02/97	Lee			
	AK	5,627,095	05/06/97	Koh et al.			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes      No
	AL	10289986	10/27/98	EPO Japan & English translation			Abs.
	AM	09074174	03/18/97	EPO Japan & English translation			Abs.
	AN	06029408	02/04/94	EPO Japan & English translation			Abs.
	AO						
	AP						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR		Serial No. 08/998,023, Parekh et al.; filed December 24, 1997.				
	AS						
	AT						
EXAMINER				DATE CONSIDERED			
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>							

EV317135518

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U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	6,458,649	10/1/2002	Zahurak et al.			
	AB	5,356,834	10/18/94	Sugimoto et al.			
	AC	5,789,289	08/04/98	Jeng			
	AD	5,933,726	08/03/99	Nishimura et al.			
	AE	5,748,521	5/1998	Lee			
	AF	5,773,342	6/1998	Fukase			
	AG	5,296,400	3/1994	Park et al.			
	AH	5,670,404	9/1997	Dai			
	AI	5,721,154	2/1998/	Jeng			
	AJ	5,789,304	8/1998	Fischer et al.			
	AK	5,792,687	8/1998	Jeng et al.			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes      No
	AL						
	AM						
	AN						
	AO						
	AP						
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